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Sm(HSeO₃)(SeO₃).2H₂O

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Abstract

The structure of samarium hydrogenselenite selenite dihydrate is characterized by layers parallel to the *xy* plane consisting of SmO₈ polyhedra linked by selenite and hydrogenselenite ions. A selenite ion links one Sm atom to three other Sm atoms while the hydrogenselenite ion acts as a monodentate bridging ligand to two Sm

atoms. The layers are held together by hydrogen bonds and van der Waals forces. The coordination polyhedron of Sm is a distorted square antiprism.

Comment

Several different crystalline phases in the system Ln-SeO₂ (where Ln is a lanthanide) have been structurally characterized. The unit-cell parameters and powder diffraction data for a compound with the formula LnH(SeO₃)₂.2.5H₂O have been reported previously (Immonen, Koskenlinna, Niinistö & Pakkanen, 1976). Several single-crystal structures of this type of compound, e.g. PrH₃(SeO₃)₂(Se₂O₅) (Koskenlinna & Valkonen, 1977a), Sc(HSeO₃)₃ (Valkonen & Leskelä, 1978), CeSe₂O₆ (Delage, Carpy, H'Naifi & Goursolle, 1986) and LaHSe₂O₆ (Morris, Harrison, Stucky & Cheetham, 1992), or with an alkali metal added to the system, e.g. NaLa(SeO₃)₂ (Morris, Hriljac & Cheetham, 1990), have been reported also. In addition, anions other than selenite can be incorporated in the structures as in the compounds Y(Se₂O₅)NO₃.3H₂O (Valkonen & Ylinen, 1979) and Er(SeO₃)(SeO₄).0.5H₂O (Morris, Wilkinson & Cheetham, 1992). The structure of the title compound has remained unsolved until now because of the severe twinning and multiple twinning of the crystals. The tendency for the crystals to be twinned may be the reason why the unit cell reported here differs from that reported earlier (Immonen, Koskenlinna, Niinistö & Pakkanen, 1976).

The title compound contains both selenite and hydrogenselenite ions. The bond distances in the selenite ion [1.680(13)–1.717(14) Å] are normal compared to those in other lanthanide selenites. The hydrogenselenite ion has one elongated Se—O bond [1.75 (2) Å] due to the bonded H atom. This bond is slightly shorter in the title compound than that in LaHSe₂O₆ (1.783 Å; Morris, Harrison, Stucky & Cheetham, 1992) or in PrH₃(SeO₃)₂(Se₂O₅) (Koskenlinna & Valkonen, 1977a), in which they vary between 1.766 and 1.805 Å.

The hydrogenselenite ion acts as a bridge between two Sm atoms. The selenite ion bridges four Sm atoms through monodentate coordination by O₆ to one Sm atom, bidentate coordination by O₁ and O₅ to a second Sm atom and the coordination of O₁ and O₅ to two other Sm atoms. Thus the three-coordinate O atoms O₁ and O₅ are bonded to Se₁ and two Sm atoms. Each OSeSm₂ group is tetrahedral in shape with an O atom at the apex. The angles Sm—HO—Se vary between 100.2 (6) and 132.9 (7)° for O₅ and 101.8 (7) and 136.4 (8)° for O₁. Three-coordinate O atoms are not uncommon in selenite compounds and are found in the structures of PrH₃(SeO₃)₂(Se₂O₅) (Koskenlinna & Valkonen, 1977a), LaHSe₂O₆ (Morris, Harrison, Stucky & Cheetham, 1992), MnSeO₃.D₂O (Koskenlinna & Valkonen, 1977b) and Ag₂SeO₃ (Okkonen, Hiltunen, Koskenlinna & Niinistö, 1994). In MnSeO₃.D₂O (Koskenlinna

& Valkonen, 1977b) the Mn—O—Se angles vary between 97.9 and 125.0°.

The structure of the title compound consists of SmO_8 coordination polyhedra arranged in layers parallel to the xy plane. Se1 connects a group of three polyhedra to one polyhedron in the x direction. The hydrogenselenite ion connects Sm atoms in the y direction. The O atoms in each SmO_8 coordination polyhedron belong to five selenite ions, two hydrogenselenite ions and one water molecule. The Sm coordination polyhedron is a distorted square antiprism, the Sm—O bond lengths being normal for eight-coordinate samarium.

The second water molecule of crystallization is situated in the cavity between the layers of SmO_8 polyhedra and Se1 atoms and is connected to O7 [2.69 (2) Å] and O6 (at $x+\frac{1}{2}$, $\frac{1}{2}-y$, $-z$) [2.87 (2) Å]. The half water

molecule observed by chemical analysis of the powder samples could not be located in the single-crystal structure.

Experimental

The title compound can be crystallized from aqueous solutions of SeO_2 and SmCl_3 within a wide range of concentration (0.1–1.0 M) and stoichiometric ratios ($\text{Sm}:\text{SeO}_2$ between 1:1 to 1:4). The crystals thus obtained are always very small and display severe twinning and multiple twinning. In order to avoid twinning the crystallization was performed in a long narrow tube by pouring a layer of 0.1 M H_2SeO_3 solution onto a 0.1 M SmCl_3 solution and carefully avoiding the mixing of the layers. After a few days at room temperature tiny needle-shaped crystals precipitated. These were washed with water, ethanol and ether. After several attempts a small single crystal suitable for data collection was obtained.

Crystal data

$\text{Sm}(\text{HSeO}_3)(\text{SeO}_3)\cdot 2\text{H}_2\text{O}$	Mo $K\alpha$ radiation
$M_r = 441.31$	$\lambda = 0.71073 \text{ \AA}$
Orthorhombic	Cell parameters from 25 reflections
$P2_12_12_1$	$\theta = 10\text{--}15^\circ$
$a = 6.6670 (10) \text{ \AA}$	$\mu = 17.083 \text{ mm}^{-1}$
$b = 7.0310 (10) \text{ \AA}$	$T = 293 (2) \text{ K}$
$c = 16.426 (3) \text{ \AA}$	Transparent needle
$V = 770.0 (2) \text{ \AA}^3$	$0.175 \times 0.030 \times 0.025 \text{ mm}$
$Z = 4$	Colourless
$D_x = 3.807 \text{ Mg m}^{-3}$	

Data collection

Rigaku AFC-7S diffractometer	$\theta_{\max} = 26.50^\circ$
$\omega-2\theta$ scans	$h = 0 \rightarrow 8$
Absorption correction:	$k = 0 \rightarrow 8$
empirical	$l = 0 \rightarrow 20$
$T_{\min} = 0.755$, $T_{\max} = 1.000$	3 standard reflections monitored every 200 reflections
953 measured reflections	intensity variation: none
953 independent reflections	
730 observed reflections	
[$I > 2\sigma(I)$]	

Refinement

Refinement on F^2	$\Delta\rho_{\max} = 2.433 \text{ e \AA}^{-3}$
$R(F) = 0.0456$	(near Sm)
$wR(F^2) = 0.0926$	$\Delta\rho_{\min} = -1.503 \text{ e \AA}^{-3}$
$S = 1.063$	Extinction correction: none
953 reflections	Atomic scattering factors, dispersion corrections and absorption coefficients from <i>International Tables for Crystallography</i> (1992, Vol. C, Tables 6.1.1.4, 4.2.6.8 and 4.2.4.2, respectively)
93 parameters	Absolute configuration: Flack (1983)
H-atom positions refined using a riding model with $U(\text{H}) = 1.5 \times U$ of atom to which it is bonded	
Calculated weights	
$w = 1/[\sigma^2(F_o^2) + (0.0358P)^2]$	
where $P = (F_o^2 + 2F_c^2)/3$	

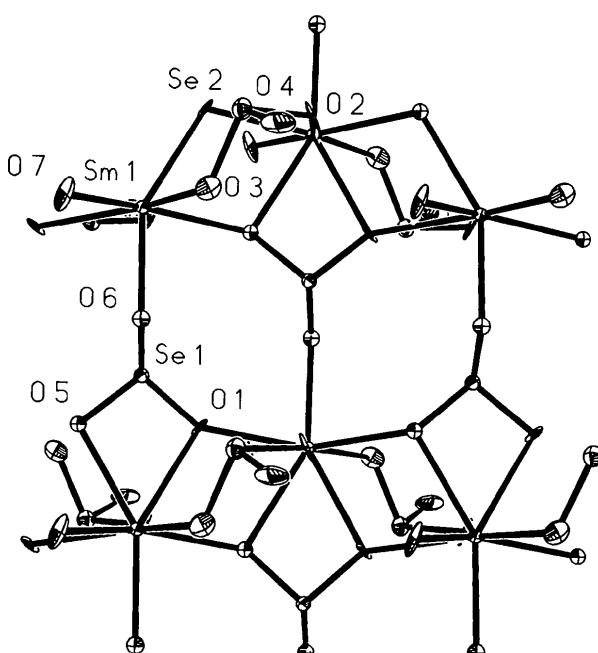


Fig. 1. O5 and O6 were refined isotropically. The H atoms and O8 are omitted for clarity.

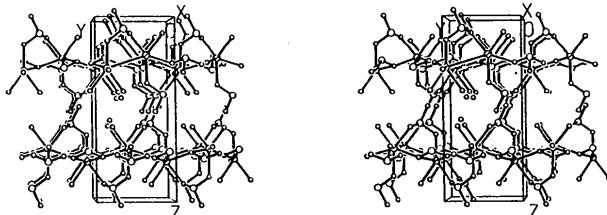


Fig. 2. A stereoview of the structure viewed along a .

Table 1. Fractional atomic coordinates and isotropic or equivalent isotropic displacement parameters (Å²)

U_{iso} for O5 and O6; $U_{\text{eq}} = (1/3)\sum_i \sum_j U_{ij} d_i^* d_j^* \mathbf{a}_i \cdot \mathbf{a}_j$ for all others.

	<i>x</i>	<i>y</i>	<i>z</i>	$U_{\text{eq}}/U_{\text{iso}}$
Sm1	0.8739 (2)	0.1095 (2)	0.78517 (7)	0.0098 (3)
Se1	0.3451 (3)	0.1143 (3)	0.72696 (12)	0.0113 (4)
Se2	1.1459 (3)	-0.1895 (3)	0.92008 (13)	0.0157 (5)
O1	0.189 (2)	-0.065 (2)	0.7564 (9)	0.017 (4)
O2	1.146 (2)	-0.387 (2)	0.8606 (8)	0.021 (3)
O3	0.917 (2)	-0.096 (3)	0.9019 (9)	0.022 (4)
O4	1.085 (2)	-0.295 (3)	1.0135 (9)	0.028 (4)
O5	0.192 (2)	0.293 (2)	0.7619 (8)	0.011 (3)
O6	0.5240 (18)	0.105 (2)	0.7989 (8)	0.013 (3)
O7	0.890 (3)	0.307 (2)	0.9049 (10)	0.031 (4)
O8	0.889 (3)	0.190 (3)	1.0607 (10)	0.051 (6)

Table 2. Selected geometric parameters (Å, °)

Sm1—O6	2.344 (12)	Sm1—O5 ⁱⁱⁱ	2.396 (14)
Sm1—O2 ⁱ	2.398 (14)	Sm1—O7	2.41 (2)
Sm1—O3	2.42 (2)	Sm1—O1 ^{iv}	2.423 (14)
Sm1—O1 ⁱⁱ	2.479 (15)	Sm1—O5 ⁱⁱ	2.513 (14)
Sm1...Sm1 ¹	4.0647 (12)	O6—O8 ^v	2.87 (2)
O7—O8	2.69 (2)	Se1—O6	1.680 (13)
Se1—O1	1.706 (14)	Se1—O5	1.717 (14)
Se2—O3	1.69 (2)	Se2—O2	1.70 (2)
Se2—O4	1.75 (2)		
O6—Sm1—O5 ⁱⁱⁱ	80.5 (5)	O6—Sm1—O2 ⁱ	92.4 (5)
O5 ⁱⁱⁱ —Sm1—O2 ⁱ	71.3 (5)	O6—Sm1—O7	88.5 (6)
O5 ⁱⁱⁱ —Sm1—O7	143.7 (5)	O2 ⁱ —Sm1—O7	144.1 (5)
O6—Sm1—O3	91.9 (5)	O5 ⁱⁱⁱ —Sm1—O3	73.9 (5)
O2 ⁱ —Sm1—O3	143.6 (5)	O7—Sm1—O3	72.1 (5)
O6—Sm1—O1 ^{iv}	82.5 (5)	O5 ⁱⁱⁱ —Sm1—O1 ^{iv}	138.9 (5)
O2 ⁱ —Sm1—O1 ⁱⁱ	82.1 (5)	O7—Sm1—O1 ⁱⁱ	113.8 (6)
O1 ^{iv} —Sm1—O1 ⁱⁱ	124.1 (4)	O5 ⁱⁱⁱ —Sm1—O5 ⁱⁱ	125.7 (3)
O2 ⁱ —Sm1—O5 ⁱⁱ	83.6 (5)	O7—Sm1—O5 ⁱⁱ	77.9 (5)
O3—Sm1—O5 ⁱⁱ	109.1 (5)	Sm1 ⁱⁱⁱ —O1—Sm1 ^{vi}	112.0 (5)
Sm1 ^{iv} —O5—Sm1 ^{vi}	111.8 (5)	Se1—O1—Sm1 ⁱⁱⁱ	136.4 (8)
Se1—O1—Sm1 ^{vi}	101.8 (7)	Se2—O2—Sm1 ^{vii}	125.8 (7)
Se2—O3—Sm1	118.7 (7)	Se1—O5—Sm1 ^{iv}	132.9 (7)
Se1—O5—Sm1 ^{vi}	100.2 (6)	Se1—O6—Sm1	129.7 (7)
O6—Se1—O1	101.7 (7)	O6—Se1—O5	102.5 (7)
O1—Se1—O5	94.9 (6)	O3—Se2—O2	102.5 (8)
O3—Se2—O4	96.2 (7)	O2—Se2—O4	99.3 (8)

Symmetry codes: (i) $2-x, \frac{1}{2}+y, \frac{3}{2}-z$; (ii) $1+x, y, z$; (iii) $1-x, y-\frac{1}{2}, \frac{3}{2}-z$; (iv) $1-x, \frac{1}{2}+y, \frac{3}{2}-z$; (v) $x-\frac{1}{2}, \frac{1}{2}-y, 2-z$; (vi) $x-1, y, z$; (vii) $2-x, y-\frac{1}{2}, \frac{3}{2}-z$.

Data collection and cell refinement: Rigaku AFC-7 software. Data reduction: TEXSAN (Molecular Structure Corporation, 1993). Program(s) used to solve structure: SIR92 (Burla *et al.*, 1992). Program(s) used to refine structure: SHELXL93 (Sheldrick, 1994). Molecular graphics: SHELXTL-Plus (Sheldrick, 1991). Software used to prepare material for publication: SHELXL93.

Lists of structure factors, anisotropic displacement parameters, H-atom coordinates and complete geometry have been deposited with the IUCr (Reference: DU1078). Copies may be obtained through The Managing Editor, International Union of Crystallography, 5 Abbey Square, Chester CH1 2HU, England.

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